

**Search Notes**

Application/Control No.

10/762,653

Examiner

Ellen C. Tran

Applicant(s)/Patent under  
Reexamination

TANAKA ET AL.

Art Unit

2134

**SEARCHED**

Class	Subclass	Date	Examiner
713	189	6/22/2007	ET
713	166, 168	6/22/2007	ET
726	25	6/22/2007	ET
380	28, 37	6/22/2007	ET
380	42	6/22/2007	ET

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
USPTO, USPG, EPO, JPO, DERWENT, IBM TECH DES	6/22/2007	ET
NPL - IEEE XPLORE	6/22/2007	ET
INVENTOR SEARCH - PALM /eDAN	6/22/2007	ET
ALL CLAIMS WERE REVIEWED FOR POSSIBLE 101 REJECTIONS	6/22/2007	ET